

OptiMOS®2 Small-Signal-Transistor

Features

- N-channel
- · Enhancement mode
- Super Logic level (2.5V rated)
- Avalanche rated
- Footprint compatible to SOT23
- dv/dt rated
- Pb-free lead plating; RoHS compliant
- Qualified according to AEC Q101

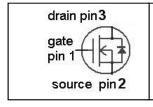




Product Summary

V _{DS}		20	V
$R_{\mathrm{DS(on),max}}$	V _{GS} =4.5 V	21	mΩ
	V _{GS} =2.5 V	33	
I _D		3.8	Α

PG-SC-59





Туре	Package	Tape and Reel Information	Marking	Lead Free	Packing
BSR202N	PG-SC-59	L6327 = 3000 pcs. / reel	LAs	Yes	Non dry

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _A =25 °C	3.8	А
		T _A =70 °C	3.1	
Pulsed drain current	I _{D,pulse}	T _A =25 °C	15.2	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =3.8 A, $R_{\rm GS}$ =25 Ω	30	mJ
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =3.8 A, $V_{\rm DS}$ =16 V, d <i>i</i> /d <i>t</i> =200 A/ μ s, $T_{\rm j,max}$ =150 °C	6	kV/μs
Gate source voltage	V_{GS}		±12	V
Power dissipation	P_{tot}	T _A =25 °C	0.5	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55 150	°C
ESD Class		JESD22-A114-HBM	0 (0V to 250V)	
Soldering Temperature			260 °C	
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol Con	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - minimal footprint	R_{thJA}		-	-	250	K/W

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA	20	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ =30 μA	0.7	0.95	1.2	
Drain-source leakage current	I _{DSS}	$V_{\rm DS}$ =20 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	-	1	μΑ
		V _{DS} =20 V, V _{GS} =0 V, T _j =150 °C	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =12 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =2.5 V, I _D =3 A	-	25	33	mΩ
		V _{GS} =4.5 V, I _D =3.8 A	-	17	21	
Transconductance	g_{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 3.8 \text{ A}$		17	1	S



Parameter	Symbol Cond	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	863	1147	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =10 V, f=1 MHz	-	278	370	
Reverse transfer capacitance	C _{rss}		-	40	60	
Turn-on delay time	t _{d(on)}	$V_{\rm DD}$ =10 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =3.8 A, $R_{\rm G}$ =6 Ω	-	8.8	_	ns
Rise time	t _r		-	16.7	_	
Turn-off delay time	$t_{d(off)}$		-	19	_	
Fall time	t _f		-	3.7	-	
Gate Charge Characteristics						
Gate to source charge	Q _{gs}		-	1.66	2.21	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =10 V, $I_{\rm D}$ =3.8 A, $V_{\rm GS}$ =0 to 4.5 V	-	1.1	1.6	
Gate charge total	Qg		-	5.8	8.8	
Gate plateau voltage	V _{plateau}		-	1.9	-	V
Reverse Diode						
Diode continous forward current	Is	- T _A =25 °C	-	-	0.8	А
Diode pulse current	I _{S,pulse}		-	-	15.2	1
Diode forward voltage	V_{SD}	V _{GS} =0 V, I _F =3.8 A, T _j =25 °C	-	0.8	1.1	V
Reverse recovery time	t _{rr}	V_{R} =10 V, I_{F} =3.8 A, di_{F}/dt =100 A/ μ s	-	14.3		ns
Reverse recovery charge	Q _{rr}		-	7.6	_	nC

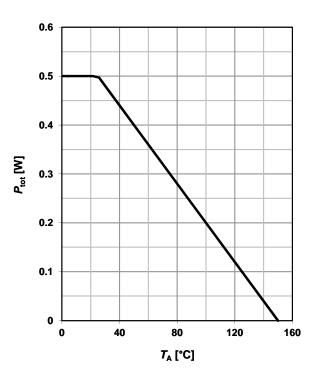


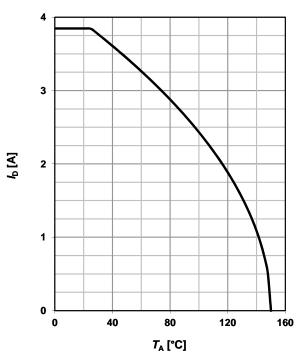
1 Power dissipation

P_{tot} =f(T_A)

2 Drain current

$$I_D = f(T_A); V_{GS} \ge 4.5 \text{ V}$$





3 Safe operating area

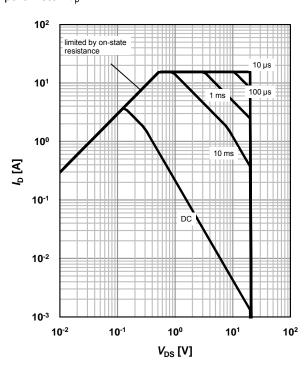
 I_D =f(V_{DS}); T_A =25 °C; D=0

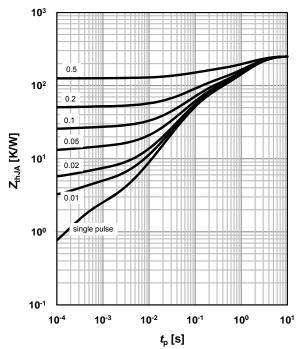
parameter: t_p

4 Max. transient thermal impedance

 Z_{thJA} = $f(t_{\mathrm{p}})$

parameter: $D=t_p/T$



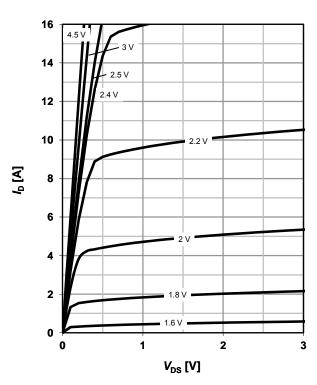




5 Typ. output characteristics

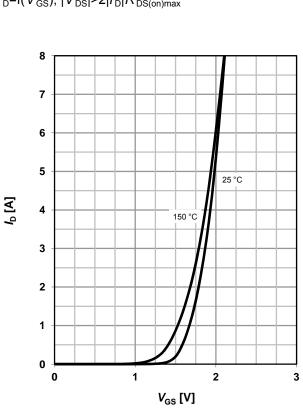
 $I_D = f(V_{DS}); T_j = 25 °C$

parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

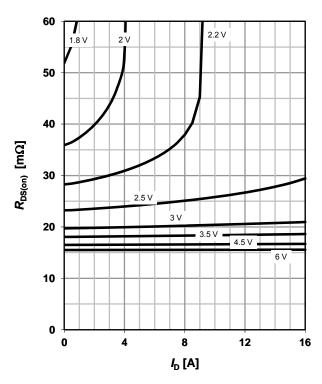
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$



6 Typ. drain-source on resistance

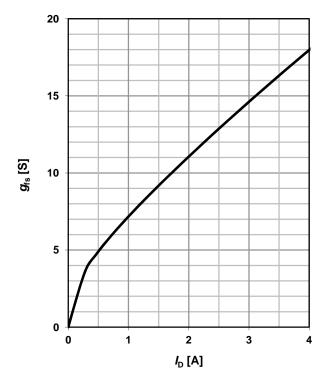
 $R_{DS(on)}=f(I_D); T_j=25 °C$

parameter: V_{GS}



8 Typ. forward transconductance

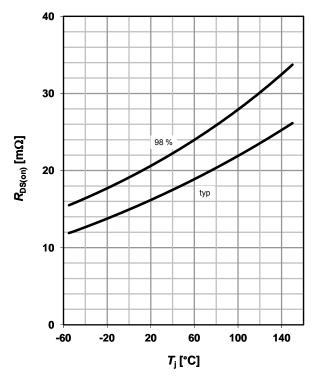
 g_{fs} =f(I_D); T_j =25 °C





9 Drain-source on-state resistance

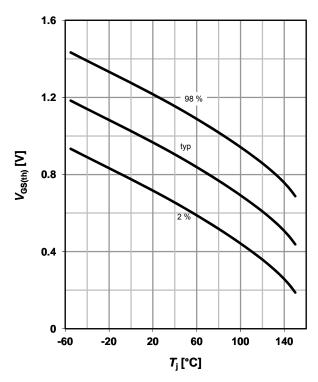
 $R_{DS(on)}$ =f(T_i); I_D =3.8 A; V_{GS} =4.5 V



10 Typ. gate threshold voltage

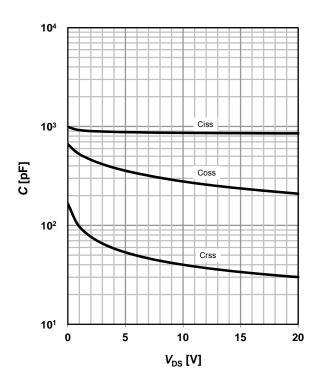
 $V_{\text{GS(th)}}$ =f(T_{j}); V_{DS} = V_{GS} ; I_{D} =30 μ A

parameter: I_D



11 Typ. capacitances

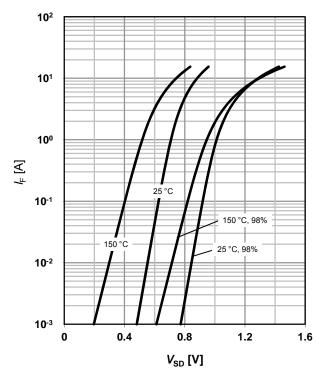
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_j=25$ °C



12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$

parameter: T_i

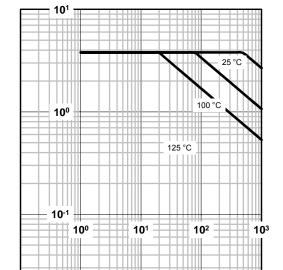




13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

parameter: $T_{j(start)}$

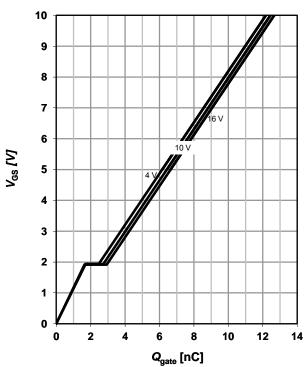


*t*_{AV} [μs]

14 Typ. gate charge

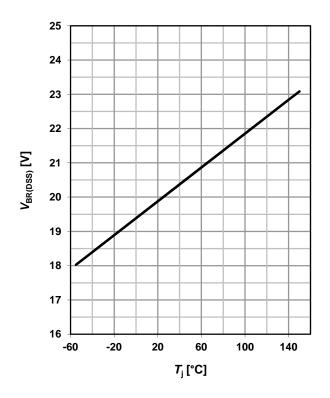
 $V_{\rm GS}$ =f($Q_{\rm gate}$); $I_{\rm D}$ =3.8 A pulsed

parameter: $V_{\rm DD}$

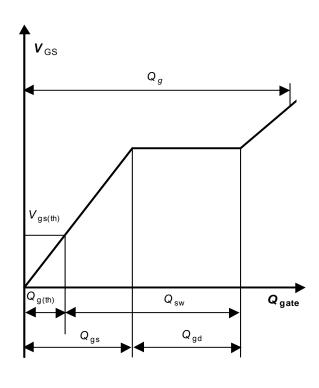


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_j); I_D =250 μ A



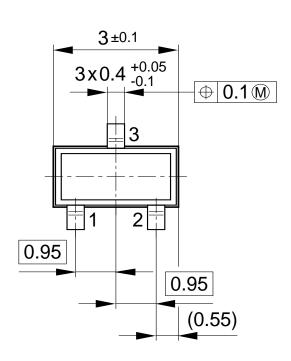
16 Gate charge waveforms

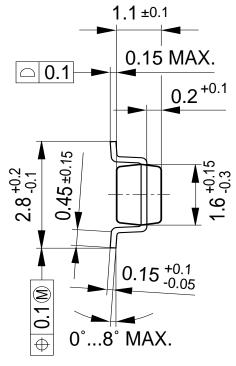




Package Outline:

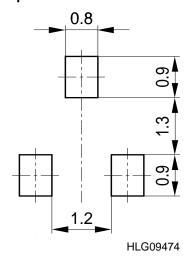
PG-SC59





GPS09473

Footprint:



Dimensions in mm



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